

Notice of References Cited	Application/Control No. 665,443	Applicant(s)/Patent Under Reexamination SUN ET AL.	
	Examiner John D. Lee <i>John D. Lee</i>	Art Unit 2874	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,063,804	12-1977	Hellwarth et al.	359/352
*	B	US-6,693,257	02-2004	Tanaka, Koichiro	219/121.76
*	C	US-2004/0135079	07-2004	Moellmann, Kyra	250/234
	D	US-			
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	I	US-			
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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